Search Notes

	Application/Control No.	Applicant(s)/Patent under Reexamination		
	10/613,216	TOYOSHIMA ET AL.	T AL.	
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	Quoc D. Tran	2614		

	SEARCHED		
Class	Subclass	Date	Examiner
379	88.19	8/6/2005	DN
	88.2		
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	93.23		
	142.01		
	142.04		
	142.06		
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379	354	8/7/2005	DN
Update	Previous searches	2/4/2006	DN

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Class	Subclass	Date	Examiner
PGPub	search history	8/23/2006	QT

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST	8/6/2005	DN
EAST	8/7/2005	DN
EAST	8/11/2005	DN
Update EAST Benny Tieu (class 379 OSS and ACD)	8/22/2006	QΤ
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Search Notes (continued)



Application/Control No.	Applicant(s)/Patent under Reexamination
10/613,216	TOYOSHIMA ET AL.
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Class	Subclass	Date	Examiner
379	207.15	8/22/2006	QT
	210.01		
	211.02	_	
	214.01	_	
	218.01	•	
	265.01	-	_
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